Power MOSFET

40 V, 4.2 m Ω , 120 A, Single N-Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	40	V
Gate-to-Source Voltage	Gate-to-Source Voltage			± 20	V
Continuous Drain Current R _{Ψ,I-mh} (Notes 1,	Steady	T _{mb} = 25°C	I _D	120	Α
2, 3, 4)		T _{mb} = 100°C		84	
Power Dissipation	State	T _{mb} = 25°C	P _D	127	W
R _{ΨJ-mb} (Notes 1, 2, 3)		T _{mb} = 100°C		64	
Continuous Drain Cur-		T _A = 25°C	I _D	21	Α
rent R _{0JA} (Notes 1, 3, 4)	Steady State	T _A = 100°C		15	
Power Dissipation		T _A = 25°C	P_{D}	3.7	W
R _{θJA} (Notes 1 & 3)		T _A = 100°C		1.9	
Pulsed Drain Current	T _A = 25	°C, t _p = 10 μs	I _{DM}	557	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to + 175	°C
Source Current (Body Diode)			Is	120	Α
Single Pulse Drain–to–Source Avalanche Energy (T _J = 25°C, V _{GS} = 10 V, $I_{L(pk)}$ = 52 A, L = 0.1 mH, R_G = 25 Ω)			E _{AS}	134	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Mounting Board (top) - Steady State (Notes 2, 3)	$R_{\Psi J-mb}$	1.2	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	40	

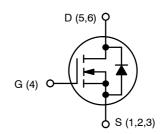
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi (Ψ) is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- 4. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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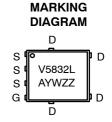
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40 V	4.2 mΩ @ 10 V	100 A
40 V	6.5 mΩ @ 4.5 V	120 A



N-CHANNEL MOSFET





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NVMFS5832NLT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NVMFS5832NLT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

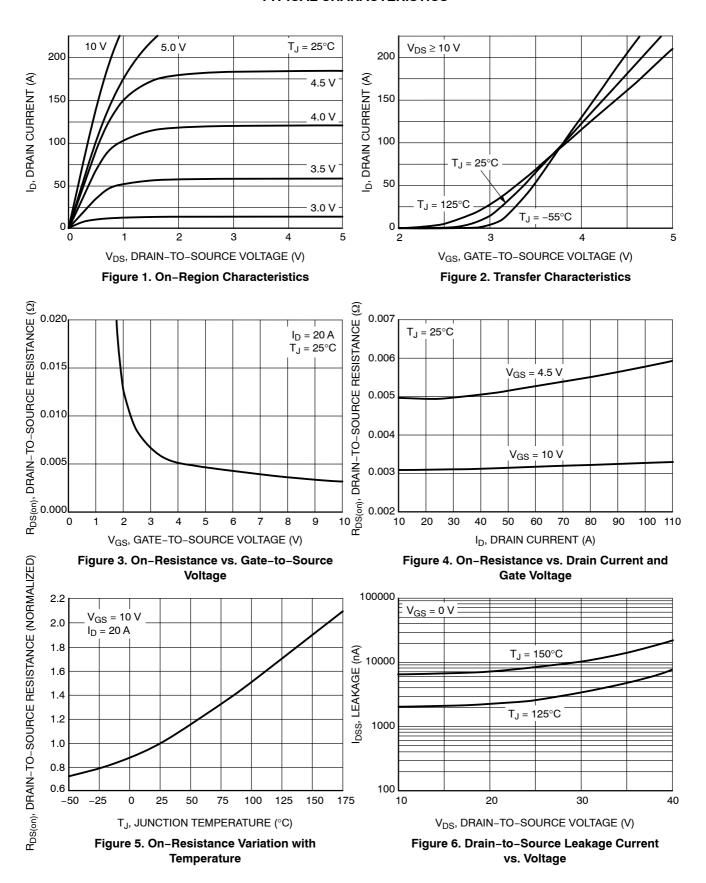
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						1	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				34.2		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$, $V_{J} = 25 °C$				1	
		$V_{DS} = 40 \text{ V}$	T _J = 125°C			100	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 5)					•	•	•
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.4		2.4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				6.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A		3.1	4.2	_
		V _{GS} = 4.5 V	I _D = 20 A		5.0	6.5	mΩ
Forward Transconductance	9FS	V _{DS} = 15 V, I _D	= 20 A		21		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE				•	•	•
Input Capacitance	C _{ISS}				2700		
Output Capacitance	C _{OSS}	$V_{GS} = 0 \text{ V, } f = 1 \text{ MHz, } V_{DS} = 25 \text{ V}$ $V_{GS} = 4.5 \text{ V, } V_{DS} = 20 \text{ V; } I_{D} = 20 \text{ A}$			360		pF
Reverse Transfer Capacitance	C _{RSS}				250		
Total Gate Charge	Q _{G(TOT)}				25		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 20 V; I _D = 20 A			51		1
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 20 V; I _D = 20 A			2.0		nC
Gate-to-Source Charge	Q _{GS}				8.0		
Gate-to-Drain Charge	Q _{GD}				12.7		
Plateau Voltage	V _{GP}				3.2		V
SWITCHING CHARACTERISTICS (Note 6)					•		•
Turn-On Delay Time	t _{d(ON)}				13		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS}$	s = 20 V.		24		1
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 10 \text{ A}, R_G = 1.0 \Omega$			27		ns
Fall Time	t _f				8.0		
DRAIN-SOURCE DIODE CHARACTERISTIC	s					1	
Forward Diode Voltage	V _{SD}	VGS - 0 V,	T _J = 25°C		0.73	1.2	
			T _J = 125°C		0.57		\ \
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 10 A			28.6		
Charge Time	ta				14		ns
Discharge Time	t _b				14.5		1
Reverse Recovery Charge	Q _{RR}				23.4		nC

^{5.} Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

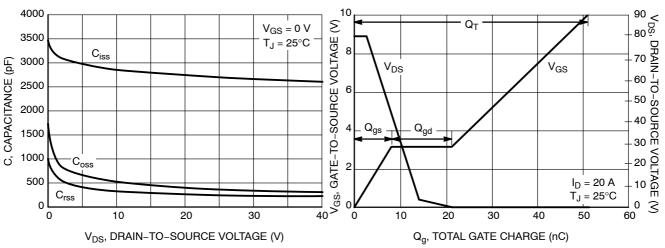


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source Voltage vs. Total Charge

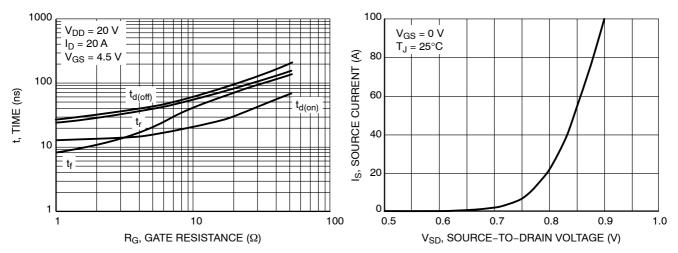


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

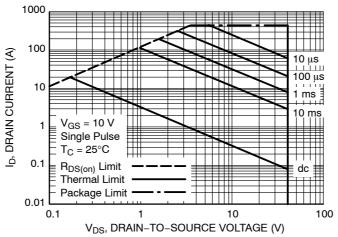


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

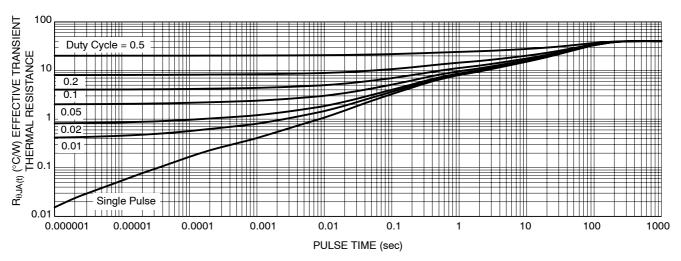
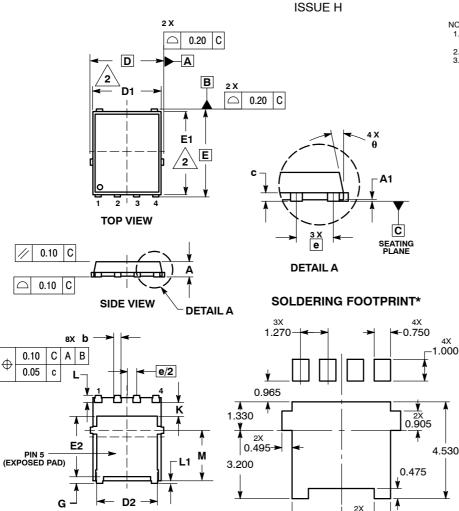


Figure 12. Thermal Response

PACKAGE DIMENSIONS





NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	1.00	1.10		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D		5.15 BSC			
D1	4.70	4.90	5.10		
D2	3.80	4.00	4.20		
E		6.15 BSC	;		
E1	5.70	5.90	6.10		
E2	3.45	3.65	3.85		
е		1.27 BSC			
G	0.51	0.61	0.71		
K	1.20	1.35	1.50		
L	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
М	3.00	3.40	3.80		
θ	0 °		12 °		

- STYLE 1: PIN 1. SOURCE
 - 2. SOURCE 3. SOURCE
 - 4. GATE 5. DRAIN

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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